



*Minnowbrook
Microelectronics*

MB'23

Dear Colleagues,

The world of high reliability microelectronic devices is rapidly advancing as new technical and material concepts are being developed to meet the demand for availability and reliability. This places a great burden on the supply houses, as the reliability of new technologies and materials needs to be proven. The reliability of hermetic device technology has been assured for decades via a multitude of testing scenarios - yet the new technologies and materials now create new concerns. Hermetic devices have gradually proven their place and now the application of non-hermetic devices in rugged environments is being advanced to allow use of devices only offered in a non-hermetic packaging. These concepts need to be proven for their respective applications. Hence, there is a need to openly discuss some of the underlying problems of the new technologies and materials, including processes and failure relates lessons learned. In addition, the efficacy and remaining issues in Test Methods 1014 (hermeticity testing) and 1018 (IGA testing) require continued attention as well as Test Method 5011 in addressing new materials.

Since Minnowbrook is based on "newer concepts in communication", it is a closed meeting (i.e., there are no abstracts, written papers, forums, publications, etc.) MB exists for open technical discussion. So - mark your calendar for attending MB'23 this October and check your email for the registration information from the Coordinator of MB'23, Tom Green.

Be Well,

Philipp wh Schuessler, (Retiring) Chairman of MB'23

Danielle Chennault Moore (Aspiring) Chairwoman of MB'23